Abstracts

A Vector Corrected Waveform and Load Line Measurement System for Large Signal Transistor Characterisation

J.G. Leckey, A.D. Patterson and J.A.C. Stewart. "A Vector Corrected Waveform and Load Line Measurement System for Large Signal Transistor Characterisation." 1995 MTT-S International Microwave Symposium Digest 95.3 (1995 Vol. III [MWSYM]): 1243-1246.

A vector corrected large signal measurement setup based on a Microwave Transition Analyser has been developed to enable device output harmonic and waveform measurement with variable drive level, frequency, DC bias and fundamental load impedance. A novel capability of this system is the ability to plot the device dynamic load lines during measurement so that nonlinear effects can be investigated as a function of bias and load impedance in real time. Load line results are shown for a MESFET and an HBT device and the effect of load impedance on device behaviour is described.

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